

Application/Control No.	Applicant(s)/Patent Reexamination	Applicant(s)/Patent under Reexamination	
10/722,884	IYER, RAVISHANKAR R.		
Examiner	Art Unit		
Matthew Bradley	2187		

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
711	158	4/15/06	MB	
711	(3 8	4/15/06	MB	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (all db's) (classified Keyward	See affacted	MB		
PACM (muentor name)	1/13/06	mB		
Christian Chace Matthew Anderson (search strategy)	49106	MB		
Brian Peugh (allowable matter)	410/06	mB		
TC 2100 - EIC Fast and focused search	1/12/06	мB		
Christian Chace;	4/11/06	MB		
Callouable matter) Brian Peugh 1 EAST	4/12/06	MB		
(uplatesearch)	ર્વાગુ૦૯ પાચલ	MB		
(inventor name search)	4/11/06	mB		
PLUS search	4/1/16	MB		